

FDS6575

Single P-Channel, Logic Level, PowerTrench™ MOSFET

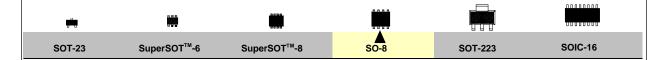
General Description

This P-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

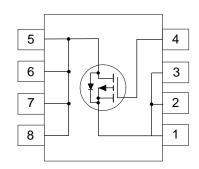
These devices are well suited for notebook computer applications: load switching and power management, battery charging circuits, and DC/DC conversion.

Features

- -10 A, -20 V. $R_{DS(ON)}$ = 0.013 Ω @ V_{GS} = -4.5 V, $R_{DS(ON)}$ = 0.017 Ω @ V_{GS} = -2.5 V.
- Low gate charge (50nC typical).
- High performance trench technology for extremely low R_{DS(ON)}.
- High power and current handling capability.







Absolute Maximum Ratings $T_A = 25^{\circ}\text{C}$ unless otherwise noted

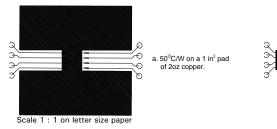
Symbol	Parameter	FDS6575	Units
V _{DSS}	Drain-Source Voltage	-20	V
V_{GSS}	Gate-Source Voltage	±8	V
I _D	Drain Current - Continuous (Note 1a)	-10	А
	- Pulsed	-50	
P_{D}	Power Dissipation for Single Operation (Note 1a)	2.5	W
	(Note 1b)	1.2	
	(Note 1c)	1	
T _J ,T _{STG}	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	CHARACTERISTICS		•
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	50	°C/W
R _{euc}	Thermal Resistance, Junction-to-Case (Note 1)	25	°C/W

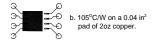
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Symbol	Parameter	Min	Тур	Max	Units	
OFF CHAI	RACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \ I_{D} = -250 \mu\text{A}$	-20			V
$\Delta BV_{DSS}/\Delta T$	Breakdown Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 $^{\circ}$ C		-19		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, \ V_{GS} = 0 \text{ V}$			-1	μA
		$T_{J} = 55^{\circ}$			-10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ON CHARA	ACTERISTICS (Note 2)		· ·			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.4	-0.8	-1.5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		3		mV/°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		0.01	0.013	Ω
		T _J =125°	С	0.015	0.02	
		$V_{GS} = -2.5 \text{ V}, I_{D} = -9 \text{ A}$		0.013	0.017	
I _{D(ON)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$	-50			Α
9 _{FS}	Forward Transconductance	$V_{DS} = -4.5 \text{ V}, I_{D} = -11 \text{ A}$		45		S
DYNAMIC	CHARACTERISTICS		•	•		
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$		4800		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		1100		pF
C _{rss}	Reverse Transfer Capacitance			460		pF
SWITCHIN	G CHARACTERISTICS (Note 2)	•	•			
t _{D(on)}	Turn - On Delay Time	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ A}$		30	50	ns
t,	Turn - On Rise Time	$V_{GEN} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		20	35	ns
t _{D(off)}	Turn - Off Delay Time			175	250	ns
t,	Turn - Off Fall Time			80	110	ns
Q_g	Total Gate Charge	$V_{DS} = -15 \text{ V}, \ I_{D} = -10 \text{ A},$		50	70	nC
Q _{qs}	Gate-Source Charge	V _{GS} = -4.5 V		8		nC
Q _{qd}	Gate-Drain Charge			11		nC
DRAIN-SO	URCE DIODE CHARACTERISTICS AND MAXIM	IUM RATINGS		•	•	•
I _s	Maximum Continuous Drain-Source Diode Fo	orward Current			-2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.1 \text{ A} \text{ (Note 2)}$		-0.7	-1.2	V

Notes:

^{1.} R_{BA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.







2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics (continued)

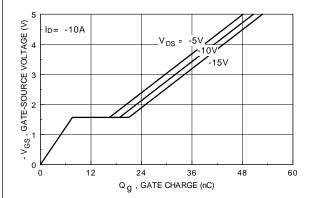
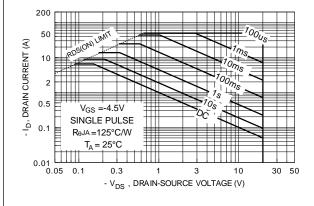


Figure 7. Gate Charge Characteristics.





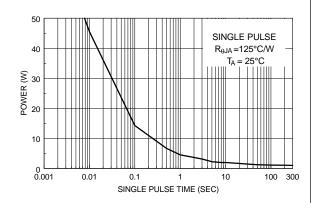
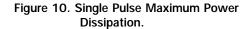


Figure 9. Maximum Safe Operating Area.



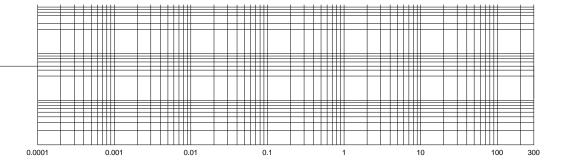
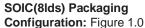


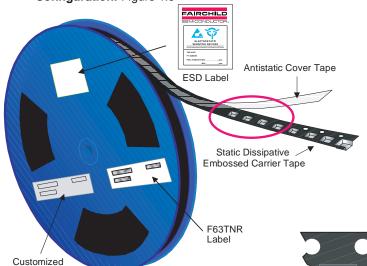
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

SO-8 Tape and Reel Data and Package Dimensions





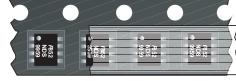


Packaging Description:

Packaging Description:

SOIC-8 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and amit-static sprayed agent. These reeled parts in standard option are shipped with 2,500 units per 13° or 300cm diameter reel. The reels are dark blue in color and is made of polystyrene plastic (antistatic coated). Other option comes in 500 units per 7° or 177cm diameter reel. This and some other options are further described in the Packaging Information table.

These full reles are individually barcode labeled and placed inside a standard intermediate box (illustrated in figure 1.0) made of recyclable corrugated brown paper. One box contains two reels maximum. And these boxes are placed inside a barcode labeled shipping box which comes in different sizes depending on the number of parts shipped.





Packaging Option Standard o flow code) L86Z D84Z Rail/Tube TNR Packaging type TNR TNR Qty per Reel/Tube/Bag 2.500 4.000 500 13" Dia 13" Dia 7" Dia 343y64y343 530x130x83 343y64y343 184v187v47 5,000 30,000 8,000 1,000

Box Dimension (mm) Max qty per Box Weight per unit (gm) 0.0774 0.0774 0.0774 0.0774 Weight per Reel (kg) 0.6060 0.9696 0.1182 Note/Comments

SOIC (8lds) Packaging Information

SOIC-8 Unit Orientation

F63TNR Label sample

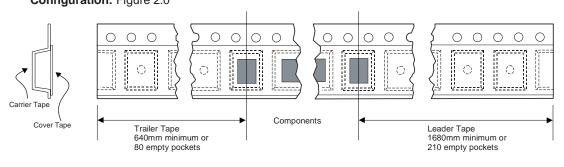
Label

Reel Size



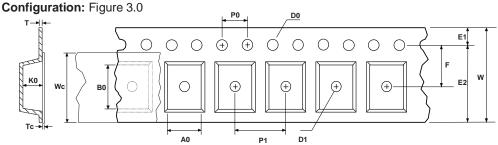
343mm x 342mm x 64mm Standard Intermediate box ESD Label F63TNL F63TN Label

SOIC(8lds) Tape Leader and Trailer Configuration: Figure 2.0





SOIC(8lds) Embossed Carrier Tape



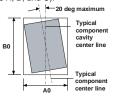


	Dimensions are in millimeter													
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SOIC(8lds) (12mm)	6.50 +/-0.10	5.30 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.60 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	2.1 +/-0.10	0.450 +/- 0.150	9.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation



Sketch B (Top View)

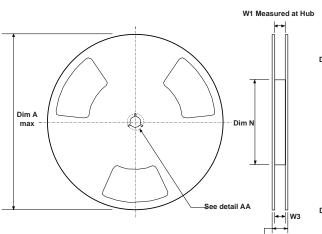
Component Rotation



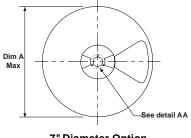
Sketch C (Top View)

Component lateral movement

SOIC(8lds) Reel Configuration: Figure 4.0



13" Diameter Option



7" Diameter Option

B Min

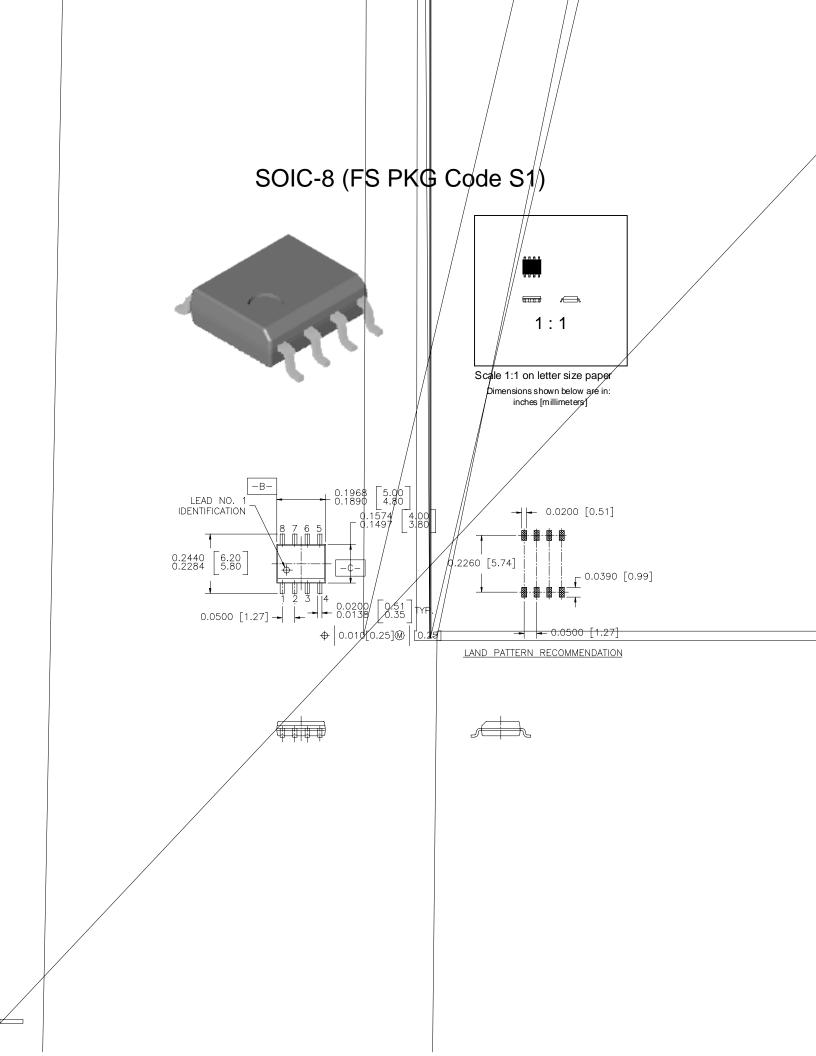
Dim C

Dim D

min

Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

W2 max Measured at Hub



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 E^2CMOS^{TM} PowerTrenchTM

FACT™ QFET™ FACT Quiet Series™ QS™

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